 arch No		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/710,551	OKUIE ET AL.
Examiner	Art Unit
Huan H. Tran	2861

	SEAR	CHED	
Class	Subclass	Date	Examiner
347	214,177 178	3/22/2006	ннт
400	207,208.1	3/22/2006	ННТ
updated		9/7/2006	ннт

INI	ERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
347/214, 177,178; 400/207,208,208.1 (text search only (USPAT;USPG_PUB;JPO;EPO;DER WENT;IBM_TDB)-see search history printout	3/22/2006	ннт	
B41J032/00;B41J017/22;B41J017/24_ text search only_see search history printout	3/22/2006	ннт	
•			